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	FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY, DOCKET NO. MICRON.272A	APPLICATION NO. 10/666,586
6	I PE INFORMATION	DISCLOSURE STATEMENT		
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
gN,	US 2002/0163828 A1	11/7/02	Krieger et al.			
aN	US 2002/0163831 A1	11/7/02	Krieger et al.			
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FOREIGN PATENT DOCUMENTS							
EXAMINER	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
INITIAL			<u> </u>			YES	NO
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BN	Advertisement for KLA-TENCOR CORPORATION, Unpatterned Surface Inspection Solution, 2 pages (2001).
4N/	Falster, "Gettering in silicon: fundamentals and recent advances," Semiconductor Fabtech, 13 th Edition, pp. 1-14 (2001).
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		RED, WHETHER OR NOT CITATION I		TH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN TO APPLICANT.